











SN74CB3Q3253

SCDS145C - OCTOBER 2003 - REVISED JUNE 2018

SN74CB3Q3253 Dual 1-of-4 FET Multiplexer – Demultiplexer 2.5-V - 3.3-V Low-Voltage High-Bandwidth Bus Switch

Features

- High-Bandwidth Data Path (Up to 500 MHz) (1)
- 5-V Tolerant I/Os With Device Powered Up or Powered Down
- Low and Flat ON-State Resistance (r_{on}) Characteristics Over Operating Range $(r_{on} = 4 \Omega Typical)$
- Rail-to-Rail Switching on Data I/O Ports
 - 0- to 5-V Switching With 3.3-V V_{CC}
 - 0- to 3.3-V Switching With 2.5-V V_{CC}
- Bidirectional Data Flow With Near-Zero Propagation Delay
- Low Input/Output Capacitance Minimizes Loading and Signal Distortion ($C_{io(OFF)} = 3.5 pF Typical$)
- Fast Switching Frequency ($f_{\overline{OE}} = 20 \text{ MHz Max}$)
- Data and Control Inputs Provide Undershoot Clamp Diodes
- Low Power Consumption ($I_{CC} = 0.6 \text{ mA Typical}$)
- V_{CC} Operating Range From 2.3 V to 3.6 V
- Data I/Os Support 0- to 5-V Signal Levels (0.8-V, 1.2-V, 1.5-V, 1.8-V, 2.5-V, 3.3-V, 5-V)
- Control Inputs Can be Driven by TTL or 5-V and 3.3-V CMOS Outputs
- I_{off} Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)
- Supports Both Digital and Analog Applications: USB Interface, Differential Signal Interface Bus Isolation, Low-Distortion Signal Gating
- For additional information regarding the performance characteristics of the CB3Q family, refer to the TI application report CBT-C, CB3T, and CB3Q Signal-Switch Families, (SCDA008).

2 Applications

- Video Broadcasting: IP-Based Multi-Format Transcoder
- Video Communications System

3 Description

The SN74CB3Q3253 device is a high-bandwidth FET bus switch using a charge pump to elevate the gate voltage of the pass transistor, providing a low and flat ON-state resistance (r_{on}). The low and flat ON-state resistance allows for minimal propagation delay and supports rail-to-rail switching on the data input and output (I/O) ports.

Device Information

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74CB3Q3253DBQ	SSOP (16)	4.90 mm × 3.90 mm
SN74CB3Q3253DGV	TVSOP (16)	3.60 mm × 4.40 mm
SN74CB3Q3253RGY	VQFN (16)	4.00 mm × 3.50 mm
SN74CB3Q3253PW	TSSOP (16)	5.00 mm × 4.40 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Logic Diagram (Positive Logic)

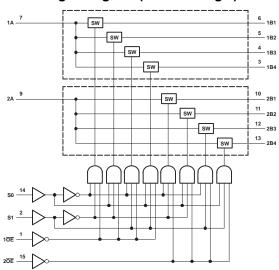




Table of Contents

1	Features 1		8.3 Feature Description	9
2	Applications 1		8.4 Device Functional Modes	9
3	Description 1	9	Application and Implementation	10
4	Revision History2		9.1 Application Information	10
5	Pin Configuration and Functions3		9.2 Typical Application	10
6	Specifications4	10	Power Supply Recommendations	11
•	6.1 Absolute Maximum Ratings	11	Layout	12
	6.2 ESD Ratings		11.1 Layout Guidelines	12
	6.3 Recommended Operating Conditions		11.2 Layout Example	12
	6.4 Thermal Information	12	Device and Documentation Support	13
	6.5 Electrical Characteristics 5		12.1 Documentation Support	13
	6.6 Switching Characteristics		12.2 Receiving Notification of Documentation Upda	ites 13
	6.7 Typical Characteristics		12.3 Community Resources	13
7	Parameter Measurement Information 7		12.4 Trademarks	13
8	Detailed Description 8		12.5 Electrostatic Discharge Caution	13
•	8.1 Overview 8		12.6 Glossary	13
	8.2 Functional Block Diagram9	13	Mechanical, Packaging, and Orderable Information	13

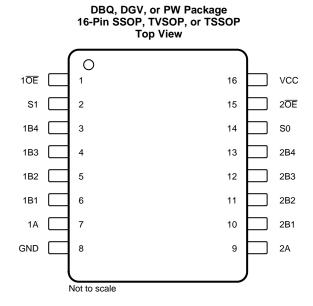
4 Revision History

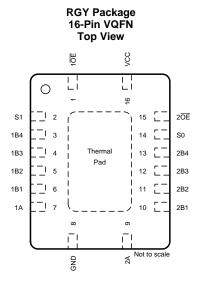
CI	Anges from Revision B (June 2015) to Revision C Changed the pinout image appearance Updated the Thermal Information table Anges from Revision A (November 2003) to Revision B Page		
•	Changed the pinout image appearance		
•	Updated the Thermal Information table		
CI	hanges from Revision A (November 2003) to Revision B	Page	
•	Removed Ordering Information table.		
•	Added Applications, Device Information table, Pin Configuration and Functions section, Storage Conditions table, ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section		

Submit Documentation Feedback



5 Pin Configuration and Functions





Pin Functions

PIN			DECODINE
NAME	NO.	I/O	DESCRIPTION
1 OE	1	I	Output Enable 1 Active-Low
S1	2	I	Select Pin 1
1B4	3	I/O	Channel 1 I/O 4
1B3	4	I/O	Channel 1 I/O 3
1B2	5	I/O	Channel 1 I/O 2
1B1	6	I/O	Channel 1 I/O 1
1A	7	I/O	Channel 1 common
GND	8	_	Ground
2A	9	I/O	Channel 2 common
2B1	10	I/O	Channel 2 I/O 1
2B2	11	I/O	Channel 2 I/O 2
2B3	12	I/O	Channel 2 I/O 3
2B4	13	I/O	Channel 2 I/O 4
S0	14	I	Select Pin 0
2 OE	15	I	Output Enable 2 Active-Low
V _{CC}	16	_	Power

Copyright © 2003–2018, Texas Instruments Incorporated

Submit Documentation Feedback



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V_{CC}	Supply voltage		-0.5	4.6	V
V_{IN}	Control input voltage (2)(3)		-0.5	7	V
V _{I/O}	Switch I/O voltage (2)(3)(4)		-0.5	7	V
I _{IK}	Control input clamp current	V _{IN} < 0		-50	mA
I _{I/OK}	I/O port clamp current	V _{I/O} < 0		– 50	mA
$I_{I/O}$	ON-state switch current (5)			±64	mA
	Continuous current through V _{CC} or GND			±100	mA
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	+2000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	+1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2.3	3.6	V
V Link lavel control investments		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	5.5	V
V _{IH}	High-level control input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	5.5	V
.,	Law law Law tool in mutual to ma	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	0.7	\/
V_{IL}	Low-level control input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0	0.8	V
$V_{I/O}$	Data input/output voltage		0	5.5	V
T _A	Operating free-air temperature		-40	85	°C

All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, (SCBA004).

Product Folder Links: SN74CB3Q3253

⁽³⁾ The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

⁽⁴⁾ V_I and V_O are used to denote specific conditions for $V_{I/O}$.

⁽⁵⁾ I_I and I_O are used to denote specific conditions for I_{I/O}.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	DBQ (SSOP)	DGV (TVSOP)	PW (TSSOP)	RGY (VQFN)	UNIT
		16 PINS	16 PINS	16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	114.3	126	112.7	45.7	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	65.4	51.3	47.5	59.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	56.8	57.8	57.85	23.3	°C/W
ΨЈТ	Junction-to-top characterization parameter	18.3	5.9	6	2.2	°C/W
ΨЈВ	Junction-to-board characterization parameter	56.4	57.3	57.3	23.4	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	11.5	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)(1)

P	ARAMETER		TEST CONDITIONS	3	MIN	TYP ⁽²⁾	MAX	UNIT
V _{IK}		V _{CC} = 3.6 V,	I _I = -18 mA				-1.8	V
I _{IN}	Control inputs	$V_{CC} = 3.6 \text{ V},$	$V_{IN} = 0 \text{ to } 5.5 \text{ V}$				±1	μΑ
$I_{OZ}^{(3)}$		V _{CC} = 3.6 V,	$V_O = 0 \text{ to } 5.5 \text{ V},$ $V_I = 0,$	Switch OFF, V _{IN} = V _{CC} or GND			±1	μΑ
I _{off}		$V_{CC} = 0$,	$V_O = 0 \text{ to } 5.5 \text{ V},$	V _I = 0			1	μA
I _{CC}		V _{CC} = 3.6 V,	I _{I/O} = 0, Switch ON or OFF,	V _{IN} = V _{CC} or GND		0.6	2	mA
ΔI _{CC} ⁽⁴⁾	Control inputs	V _{CC} = 3.6 V,	One input at 3 V,	Other inputs at V _{CC} or GND			30	μA
(5)	Per control input	V _{CC} = 3.6 V,	A and B ports open,	OE input		0.15	0.16	mA/
I _{CCD} ⁽⁵⁾		Control input switchin	ng at 50% duty cycle	S input		0.04	0.05	MHz
C _{in}	Control inputs	$V_{CC} = 3.3 \text{ V},$	V _{IN} = 5.5 V, 3.3 V, or	0		2.5	3.5	pF
C	A port	V _{CC} = 3.3 V,	Switch OFF, $V_{IN} = V_{CC}$ or GND,	$V_{I/O} = 5.5 \text{ V}, 3.3 \text{ V}, \text{ or } 0$		8	11	pF
C _{io(OFF)}	B port	V _{CC} = 3.3 V,	Switch OFF, V _{IN} = V _{CC} or GND,	$V_{I/O} = 5.5 \text{ V}, 3.3 \text{ V}, \text{ or } 0$		3.5	4.5	pF
C _{io(ON)}	,	V _{CC} = 3.3 V,	Switch ON, V _{IN} = V _{CC} or GND,	$V_{I/O} = 5.5 \text{ V}, 3.3 \text{ V}, \text{ or } 0$		13	17	pF
		V _{CC} = 2.3 V,	$V_I = 0$,	I _O = 30 mA		4	10	
r _{on} (6)		TYP at $V_{CC} = 2.5 \text{ V}$	V _I = 1.7 V,	I _O = -15 mA		4.5	11	Ω
Ion`′		\/ - 2 \/	$V_I = 0$,	I _O = 30 mA		3.5	8	12
		$V_{CC} = 3 V$	$V_1 = 2.4 V,$	$I_O = -15 \text{ mA}$		4	10	

- (3)
- V_{IN} and I_{IN} refer to control inputs. V_I , V_O , I_I , and I_O refer to data pins. All typical values are at $V_{CC}=3.3~V$ (unless otherwise noted), $T_A=25^{\circ}C$. For I/O ports, the parameter I_{OZ} includes the input leakage current. This is the increase in supply current for each input that is at the specified TTL voltage level, rather than V_{CC} or GND.
- This parameter specifies the dynamic power-supply current associated with the operating frequency of a single control input (see Figure 2).
- Measured by the voltage drop between the A and B terminals at the indicated current through the switch. ON-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

Product Folder Links: SN74CB3Q3253

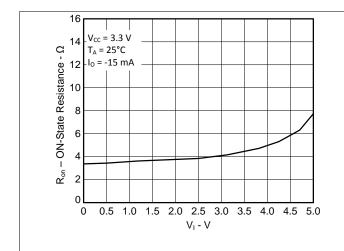


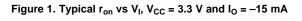
6.6 Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM	TO	V _{CC} = 2 ± 0.2	2.5 V V	V _{CC} = 3 ± 0.3	3.3 V 3 V	UNIT
	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	
$f \overline{OE}$ or $f_S^{(1)}$	OE or S	A or B		10		20	MHz
$t_{pd}^{(2)}$	A or B	B or A		0.12		0.18	ns
$t_{pd(s)}$	S	Α	1.5	6.7	1.5	5.9	ns
4	S	В	1.5	6.7	1.5	5.9	
t _{en}	ŌE	A or B	1.5	6.7	1.5	5.9	ns
4	S	В	1	6.1	1	6.1	20
t _{dis}	ŌĒ	A or B	1	6.1	1	6.1	ns

6.7 Typical Characteristics





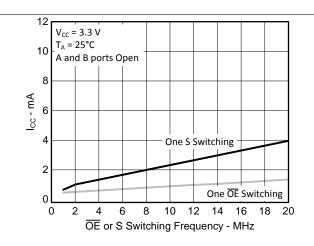


Figure 2. Typical I_{CC} vs \overline{OE} or S Switching Frequency, $V_{CC} = 3.3 V$

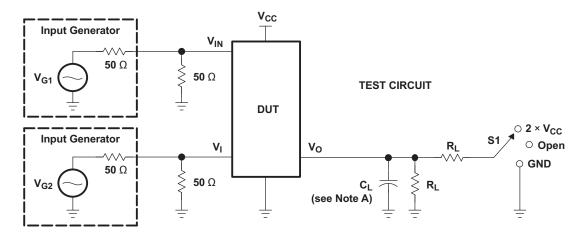
Submit Documentation Feedback

Copyright © 2003-2018, Texas Instruments Incorporated

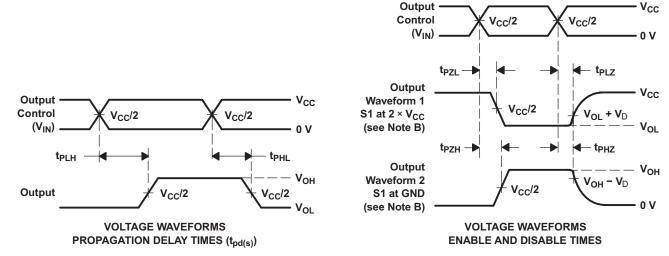
Maximum switching frequency for control input ($V_O > V_{CC}$, $V_I = 5$ V, $R_L \ge 1$ M Ω , $C_L = 0$). The propagation delay is the calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).



7 Parameter Measurement Information



TEST	V _{CC}	S1	R_{L}	VI	CL	$oldsymbol{V}_\Delta$
t _{pd(s)}	2.5 V ± 0.2 V 3.3 V ± 0.3 V	Open Open	500 Ω 500 Ω	V _{CC} or GND V _{CC} or GND	30 pF 50 pF	
t _{PLZ} /t _{PZL}	2.5 V ± 0.2 V 3.3 V ± 0.3 V	2 × V _{CC} 2 × V _{CC}	500 Ω 500 Ω	GND GND	30 pF 50 pF	0.15 V 0.3 V
t _{PHZ} /t _{PZH}	2.5 V ± 0.2 V 3.3 V ± 0.3 V	GND GND	500 Ω 500 Ω	V _{CC}	30 pF 50 pF	0.15 V 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{O} = 50 W, $t_{r} \leq$ 2.5 ns, $t_{f} \leq$ 2.5 ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. t_{PLH} and t_{PHL} are the same as t_{pd(s)}. The tpd propagation delay is the calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).
- H. All parameters and waveforms are not applicable to all devices.

Figure 3. Test Circuit and Voltage Waveforms

Submit Documentation Feedback



8 Detailed Description

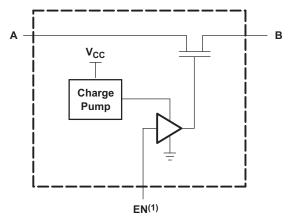
8.1 Overview

The SN74CB3Q3253 device is a high-bandwidth FET bus switch using a charge pump to elevate the gate voltage of the pass transistor, providing a low and flat ON-state resistance (r_{on}). The low and flat ON-state resistance allows for minimal propagation delay and supports rail-to-rail switching on the data input/output (I/O) ports. The device also features low data I/O capacitance to minimize capacitive loading and signal distortion on the data bus. Specifically designed to support high-bandwidth applications, the SN74CB3Q3253 device provides an optimized interface solution ideally suited for broadband communications, networking, and data-intensive computing systems.

The SN74CB3Q3253 device is organized as two 1-of-4 multiplexers/demultiplexers with separate output-enable (1OE, 2OE) inputs. The select (S0, S1) inputs control the data path of each multiplexer/demultiplexer. When OE is low, the associated multiplexer/demultiplexer is enabled, and the A port is connected to the B port, allowing bidirectional data flow between ports. When OE is high, the associated multiplexer/demultiplexer is disabled, and a high-impedance state exists between the A and B ports.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry prevents damaging current backflow through the device when it is powered down. The device has isolation during power off.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.



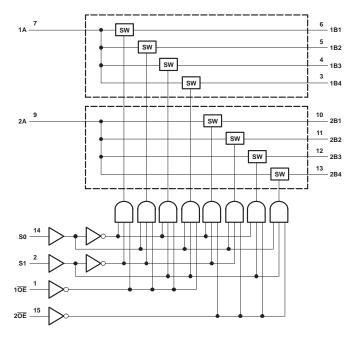
(1) EN is the internal enable signal applied to the switch.

Figure 4. Simplified Schematic, Each FET Switch (SW)

Submit Documentation Feedback



8.2 Functional Block Diagram



8.3 Feature Description

The SN74CB3Q3253 device has a high-bandwidth data path (up to 500 MHz) and has 5-V tolerant I/Os with the device powered up or powered down. It also has low and flat ON-state resistance (r_{on}) characteristics over operating range (r_{on} = 4 Ω Typical)

This device also has rail-to-rail switching on data I/O ports for 0- to 5-V switching with 3.3-V V_{CC} and 0- to 3.3-V switching with 2.5-V V_{CC} as well as bidirectional data flow with near-zero propagation delay and low input and output capacitance that minimizes loading and signal distortion ($C_{io(OFF)} = 3.5$ pF Typical)

The SN74CB3Q3253 also provides a fast switching frequency ($f_{\overline{OE}} = 20$ MHz Maximum) with data and control inputs that provide undershoot clamp diodes as well as low power consumption ($I_{CC} = 0.6$ mA Typical)

The V_{CC} operating range is from 2.3 V to 3.6 V and the data I/Os support 0- to 5-V signal levels of (0.8-V, 1.2-V, 1.5-V, 1.8-V, 2.5-V, 3.3-V, 5-V)

The control inputs can be driven by TTL or 5-V and 3.3-V CMOS outputs as well as I_{off} Supports Partial-Power-Down Mode Operation

8.4 Device Functional Modes

Table 1 lists the functional modes of the SN74CB3Q3253.

Table 1. Function Table (Each Multiplexer/Demultiplexer)

	INPUTS		INPUT/OUTPUT	FUNCTION
ŌĒ	S1	S0	Α	FUNCTION
L	L	L	B1	A port = B1 port
L	L	Н	B2	A port = B2 port
L	Н	L	В3	A port = B3 port
L	Н	Н	B4	A port = B4 port
Н	Х	Х	Z	Disconnect

Product Folder Links: SN74CB3Q3253



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The SN74CB3Q3253 device can be used to multiplex and demultiplex up to 4 channels simultaneously in a 2:1 configuration.

9.2 Typical Application

The application shown here is a 4-bit bus being multiplexed between two devices. the \overline{OE} and S pins are used to control the chip from the bus controller. This is a very generic example, and could apply to many situations. If an application requires less than 4 bits, be sure to tie the A side to either high or low on unused channels.

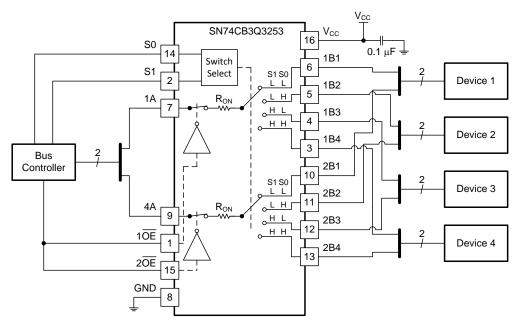


Figure 5. Typical Application of the SN74CB3Q3253

9.2.1 Design Requirements

The 0.1-µF capacitor should be place as close as possible to the device.

9.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions:
 - For specified high and low levels, see V_{IH} and V_{IL} in Recommended Operating Conditions.
 - Inputs and outputs are overvoltage tolerant slowing them to go as high as 4.6 V at any valid V_{CC}.
- 2. Recommended Output Conditions:
 - Load currents should not exceed ±128 mA per channel.
- 3. Frequency Selection Criterion:
 - Maximum frequency tested is 500 MHz.
 - Added trace resistance and capacitance can reduce maximum frequency capability; use layout practices as directed in *Layout*.

Submit Documentation Feedback

Copyright © 2003–2018, Texas Instruments Incorporated



Typical Application (continued)

9.2.3 Application Curve

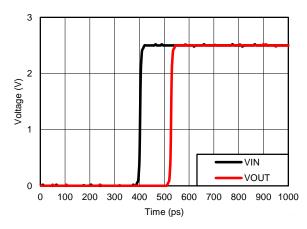


Figure 6. Propagation Delay (t_{pd}) Simulation Result at $V_{CC} = 2.5 \text{ V}$

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating listed in the *Absolute Maximum Ratings* table.

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- μ F bypass capacitor is recommended. If multiple pins are labeled V_{CC} , then a 0.01- μ F or 0.022- μ F capacitor is recommended for each V_{CC} because the V_{CC} pins are tied together internally. For devices with dual-supply pins operating at different voltages, for example V_{CC} and V_{DD} , a 0.1- μ F bypass capacitor is recommended for each supply pin. To reject different frequencies of noise, use multiple bypass capacitors in parallel. Capacitors with values of 0.1 μ F and 1 μ F are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

Product Folder Links: SN74CB3Q3253



11 Layout

11.1 Layout Guidelines

Reflections and matching are closely related to the loop antenna theory but are different enough to be discussed separately from the theory. When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. Figure 7 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

11.2 Layout Example

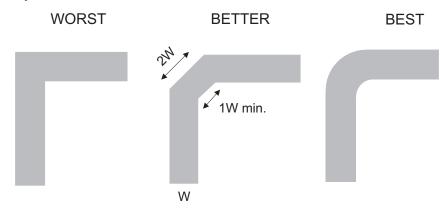


Figure 7. Trace Example

Submit Documentation Feedback



12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Implications of Slow or Floating CMOS Inputs, SCBA004
- Selecting the Right Texas Instruments Signal Switch, SZZA030

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: SN74CB3Q3253





7-Jun-2018

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
74CB3Q3253DBQRG4	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BU253	Samples
74CB3Q3253RGYRG4	ACTIVE	VQFN	RGY	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BU253	Samples
SN74CB3Q3253DBQR	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BU253	Samples
SN74CB3Q3253DGVR	ACTIVE	TVSOP	DGV	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253PWRE4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253PWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	BU253	Samples
SN74CB3Q3253RGYR	ACTIVE	VQFN	RGY	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BU253	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



PACKAGE OPTION ADDENDUM

7-Jun-2018

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 7-Jun-2018

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All differsions are norminal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74CB3Q3253DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
SN74CB3Q3253DGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74CB3Q3253PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74CB3Q3253RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1

www.ti.com 7-Jun-2018



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74CB3Q3253DBQR	SSOP	DBQ	16	2500	340.5	338.1	20.6
SN74CB3Q3253DGVR	TVSOP	DGV	16	2000	367.0	367.0	35.0
SN74CB3Q3253PWR	TSSOP	PW	16	2000	367.0	367.0	35.0
SN74CB3Q3253RGYR	VQFN	RGY	16	3000	367.0	367.0	35.0

DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194 PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153





Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MO-137, variation AB.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



IMPORTANT NOTICE

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's non-compliance with the terms and provisions of this Notice.